# Fast Ultra High-PSRR, Low-Noise, Low-Dropout, 150mA Micropower CMOS Linear Regulator

## **General Description**

The EMP891X series is a family of CMOS linear regulators, which include EMP8915 and EMP8916, featuring ultra-high power supply rejection ratio, low output voltage noise, low dropout voltage, low quiescent current and fast transient response. EMP891X guarantees delivery of 150mA output current, and supports preset 1.2V, 1.3V, 1.5V, 1.8V, 2.5V, 2.8V, 2.85V output voltage versions.

Based on its low quiescent current consumption and its less than  $1\mu A$  shutdown mode of logical operation, the EMP891X series are ideal for battery-powered applications. The ground current increases only slightly in dropout, further prolonging the battery life.

EMP891X series provide fast turn-on by using dedicated circuitry to pre-charge an optional external bypass capacitor. This bypass capacitor is used to reduce the output voltage noise without adversely affecting the load transient response. The high power supply rejection ratio of the EMP891X holds well for low input voltages typically encountered in battery-operated systems. The regulator is stable with small ceramic capacitive loads (2.2µF typical).

Additional features include regulation fault detection, bandgap voltage reference, constant current limiting and thermal overload protection. Available in miniature SOT-25, SOT-26 and TDFN-6 packages, the EMP891X series are suitable for portable appliances.

EMP products is RoHS compliant.

#### **Features**

- Miniature SOT-25, SOT-26 and TDFN-6 packages
- 150mA guaranteed output current
- 75dB typical PSRR at 1kHz (60dB typical at 10KHz)
- 30µV RMS output voltage noise (10Hz to 100kHz)
- 65mV typical dropout at 150mA
- 106µA typical quiescent current
- Less than 1µA typical shutdown mode
- Fast line and load transient response
- 80µs typical fast turn-on time
- 2.5V to 5.5V input range
- Stable with small ceramic output capacitors
- Over temperature and over current protection
- ±2% output voltage tolerance
- ±1% output voltage tolerance for Vout 1.5V

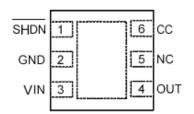
## **Applications**

- Wireless handsets
- PCMCIA cards
- DSP core power
- Hand-held instruments
- Battery-powered systems
- Portable information appliances



# **Connection Diagrams**

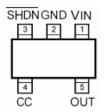
#### TDFN-6(TOP VIEW)



Note: Version also available for pin #1 as

FAULT pin and pin #5 as SHDN pin

#### SOT-25(TOP VIEW)



EMP8915-XXFE06GRR

Order information

XX Operation Code FE06 TDFN-6 Package

NRR RoHS & Halogen free package

Commercial Grade Temperature

Rating: -40 to 85°C Package in Tape & Reel

#### EMP8915-XXVF05GRR

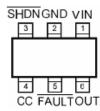
XXOperation Code VF05 SOT-25 Package GRR RoHS package

Commercial Grade Temperature

Rating: -40 to 85°C

Package in Tape & Reel

#### SOT-26(TOP VIEW)



## EMP8916-XXVC06GRR

XX Operation Code VC06 SOT-26 Package GRR RoHS package

Commercial Grade Temperature

Rating: -40 to 85°C

Package in Tape & Reel



# Marking & Packing Information

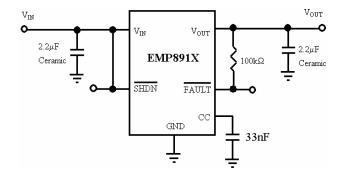
No. of	EN	СС	Fault	Package	Marki	ing	Vout	Product ID	
PIN	LIV		rauit	rackage	new	Old (8935/8915)	Vout	Floddet ID	
						Date code; P621/P611	1.2	EMP8915-12VF05GRR	
						Date code;/P612	1.3	EMP8915-13VF05GRR	
						Date code; P624/P614	1.5	EMP8915-15VF05GRR	
_	V	,		007.05	оит сс Б 4 8935	Date code; P627/P617	1.8	EMP8915-18VF05GRR	
5	Y	Y	Ν	SOT-25	Tracking Code    BIN1 DOT   1 2 3	Date code; P62E/P61E	2.5	EMP8915-25VF05GRR	
					VIN GRND SHDN  OUT CC 5 4  8915  Tracking Code  1 2 3  VIN GRND SHDN	VIN GRND SHDN	Date code; P62H/P61H	2.8	EMP8915-28VF05GRR
						Date code;/P61N	2.85	EMP8915-2QVF05GRR	
							1.2	EMP8916-12VC06GRR	
					OUT.FAULT		1.3	EMP8916-13VC06GRR	
					8916		1.5	EMP8916-15VC06GRR	
6	Υ	Υ	Υ	SOT-26	Tracking C	· I	1.8	EMP8916-18VC06GRR	
					PINI DOT VIN CND	TET .	2.5	EMP8916-25VC06GRR	
					VIN GND	SHDN	2.8	EMP8916-28VC06GRR	
							2.85	EMP8916-2QVC06GRR	
							1.2	By request	
						4	1.3	By request	
					8915	1	1.5	By request	
5	Υ	Υ	Y N	TDFN-6	Tracking C	,	1.8	By request	
					PIN1 DOT	m	2.5	By request	
					[HMI DOI]		2.8	By request	
							2.85	By request	

Publication Date: Mar. 2009 Revision: 5.0 3/21



					2	1.2	By request
					9 9 4	1.3	By request
					8916	1.5	By request
6	Υ	Υ	Y	TDFN-6	Tracking Code	1.8	By request
					1 P N E	2.5	By request
					PIN1 DOT	2.8	By request
						2.85	By request

# **Typical Application**





# **Pin Functions**

Name	SOT-25	SOT-26	TDFN-6	Function
VOUT	5	6	4	Output Voltage Feedback.
VIN	1	1	3	Supply Voltage Input. Require a minimum input capacitor of close to 1µF to ensure stability and sufficient decoupling from the ground pin.
GND	2	2	2	Ground Pin.
NC			5 or N/A	No Connection
СС	4	4	6	Compensation Capacitor. Connect an optimum 33nF noise bypass capacitor between the CC and the ground pins to reduce noise in VOUT.
SHDN	3	3	1 or 5	Shutdown Input. Set the regulator into the disable mode by pulling the SHDN pin low. To keep the regulator on during normal operation, connect the SHDN pin to VIN. The SHDN pin must not exceed VIN under all operating conditions.
FAULT		5	N/A or 1	Fault Detection Output. The $\overline{\text{FAULT}}$ pin goes low when the voltage regulating function fails. Because the $\overline{\text{FAULT}}$ pin connects to the open-drain output of a NMOS transistor, a typical 100k $\Omega$ pull-up resistor is required to provide the necessary output voltage. The $\overline{\text{FAULT}}$ pin enters the high impedance state during shutdown and it should be connected to ground if unused.



Absolute Maximum Ratings (Notes 1, 2) Thermal Resistance (0JA)

TDFN-6 (Note 3)

VIN,  $V_{OUT}$ ,  $V_{SHDN}$ ,  $V_{SET}$ ,  $V_{CC}$ ,  $V_{FAULT}$  -0.3V to 6.5V SOT-25

Power Dissipation (Note 3) SOT-26 250°C/W

Storage Temperature Range -65°C to160°C

Junction Temperature (TJ) 150°C

Lead Temperature (10 sec.) 260°C Operating Ratings (Note 1, 2)

ESD Rating Temperature Range -40°C to 85°C

Human Body Model (Note 5) 2kV Supply Voltage 2.5V to 5.5V

## **Electrical Characteristics**

Unless otherwise specified, all limits guaranteed for  $V_{IN} = V_{OUT} + 0.5V$  (Note 6),  $V_{SHDN} = V_{IN}$ ,  $C_{IN} = C_{OUT} = 2.2\mu F$ ,  $C_{CC} = 33nF$ ,  $T_J = 25^{\circ}C$ . **Boldface** limits apply for the operating temperature extremes: -40°C and 85°C.

Symbol	Parameter	Conditions	Min	Typ (Note 7)	Max	Units	
V <sub>IN</sub>	Input Voltage		2.5		5.5	V	
	Output Voltage Tolerance	$100\mu A \le I_{OUT} \le 150mA$ $V_{IN} = V_{OUT (NOM)} + 0.5V, (Note 6)$	-2		+2	% of V <sub>OUT (NOM)</sub>	
ΔVoτL	1.5V output Voltage Tolerance	$100\mu A \le I_{OUT} \le 150mA$ $V_{IN} = V_{OUT (NOM)} + 0.5V, (Note 6)$	-1		+1	% of Vout (NOM)	
Іоит	Maximum Output Current	Average DC Current Rating	150			mA	
I <sub>LIMIT</sub>	Output Current Limit		165	280		mA	
		I <sub>OUT</sub> = 0mA		106	210	μA	
IQ	Supply Current	I <sub>OUT</sub> = 150mA		145			
	Shutdown Supply Current	V <sub>OUT</sub> = 0V, SHDN = GND		0.001			
	D 137 II	I <sub>OUT</sub> = 1mA		0.03		mV	
$V_{DO}$	Dropout Voltage	I <sub>OUT</sub> = 50mA		22			
	(Note 4), (Note 6)	I <sub>OUT</sub> = 150mA		65			
		f = 100Hz		74		dB	
DCDD	Power-supply rejection ratio	f = 1kHz		75			
PSRR	VIN=3.5V, V <sub>OUT</sub> =2.5V	f = 10kHz		60			
	Iout=50mA	f = 100kHz		36			
$\Delta V_OUT$	Line Regulation	$I_{OUT} = 1 \text{mA}, (V_{OUT} + 0.5 \text{V}) \le V_{IN}$ $\le 5.5 \text{V}, (Note 7)$		0.02		%/V	
	Load Regulation	100μA ≤ I <sub>OUT</sub> ≤ 150mA		0.0004		%/mA	
en	Output Voltage Noise	$I_{OUT} = 10 \text{mA}, 10 \text{Hz} \le f \le 100 \text{kHz}$		30		$\mu V_{RMS}$	
V =	CLIDN languat Through and	$V_{IH}$ , $(V_{OUT} + 0.5V) \le V_{IN} \le 5.5V$ (Note 6)	1.2			· V	
V shdn	SHDN Input Threshold	$V_{IL}$ , $(V_{OUT} + 0.5V) \le V_{IN} \le 5.5V$ (Note 6)			0.4		
Ishdn	SHDN Input Bias Current	SHDN = GND or VIN		0.1	100	nA	
V FAULT	FAULT Detection Voltage	$V_{OUT} \ge 2.5V$ , $I_{OUT} = 150mA$ (Note 8)		95		mV	

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Publication Date: Mar. 2009 Revision: 5.0 **6/21** 

	FAULT Output Low Voltage	I <sub>SINK</sub> = 2mA	0.2		٧
FAULT	FAULT Off-Leakage Current	$\overline{\text{FAULT}} = 3.6\text{V}, \ \overline{\text{SHDN}} = 0\text{V}$	0.1	100	nA
T <sub>SD</sub>	Thermal Shutdown Temperature		165		°C
	Thermal Shutdown Hysteresis		30		
T <sub>ON</sub>	Turn-On Time	Vout at 95% of Final Value	80		μs

- **Note 1:** Absolute Maximum ratings indicate limits beyond which damage may occur. Electrical specifications are not applicable when the device is operated outside of its rated operating conditions.
- Note 2: All voltages are defined and measured with respect to the potential at the ground pin.
- Note 3: Maximum Power dissipation for the device is calculated using the following equations:

$$P_D = \frac{T_J(MAX) - T_A}{\theta_{JA}}$$

where  $T_{J[MAX]}$  is the maximum junction temperature,  $T_A$  is the ambient temperature, and  $\theta_{JA}$  is the junction-to-ambient thermal resistance. E.g. for the SOT-25 package  $\theta_{JA} = 250^{\circ}\text{C/W}$ ,  $T_{J[MAX]} = 150^{\circ}\text{C}$  and using  $T_A = 25^{\circ}\text{C}$ , the maximum power dissipation is found to be 500mW. The derating factor  $(-1/\theta_{JA}) = -4\text{mW/°C}$ , thus below 25°C the power dissipation figure can be increased by 4mW per degree, and similarity decreased by this factor for temperatures above 25°C. The value of the  $\theta_{JA}$  for the TDFN package is specifically dependent on the PCB trace area, trace material, and the number of layers and thermal vias.

- Note 4: Dropout voltage is measured by reducing  $V_{IN}$  until  $V_{OUT}$  drops 100mV from its nominal value at  $V_{IN}$  - $V_{OUT}$  = 0.5V. Dropout voltage does not apply to the regulator versions with  $V_{OUT}$  less than 2.5V.
- **Note 5**: Human body model:  $1.5k\Omega$  in series with 100pF.
- Note 6: Condition does not apply to input voltages below 2.5V since this is the minimum input operating voltage.
- Note 7: Typical Values represent the most likely parametric norm.
- Note 8: The FAULT detection voltage is specified for the input to output voltage differential at which the FAULT pin goes active low.

Revision: 5.0



# **Functional Block Diagram**

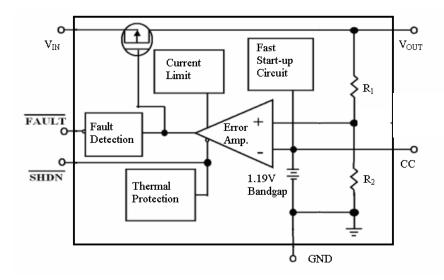
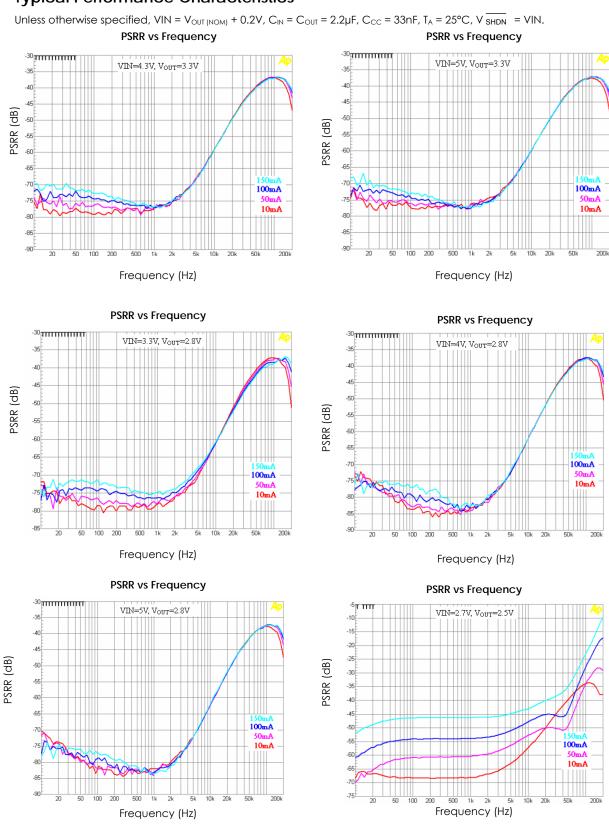


Fig.1. EMP891X Functional Block Diagram

Publication Date: Mar. 2009 Revision: 5.0 **8/21** 



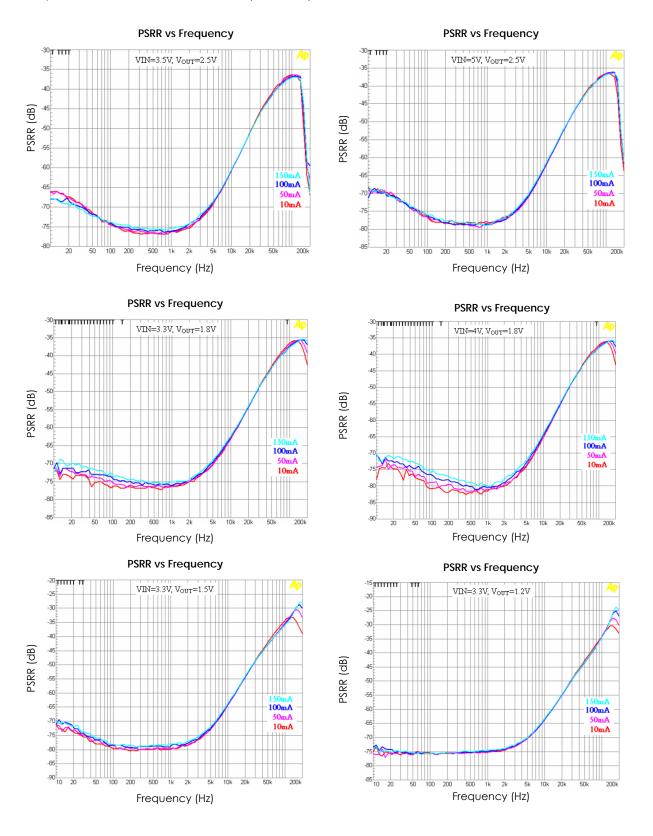
# **Typical Performance Characteristics**



Publication Date: Mar. 2009 Revision: 5.0 9/21

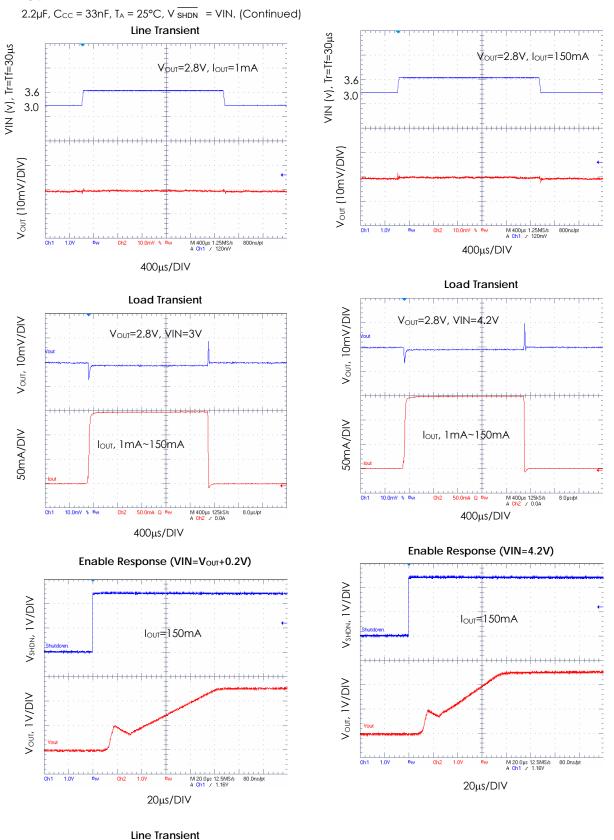


**Typical Performance Characteristics** Unless otherwise specified, VIN =  $V_{OUT (NOM)} + 0.2V$ ,  $C_{IN} = C_{OUT} = 2.2\mu F$ ,  $C_{CC} = 33nF$ ,  $T_A = 25^{\circ}C$ ,  $V_{\overline{SHDN}} = VIN$ . (Continued)



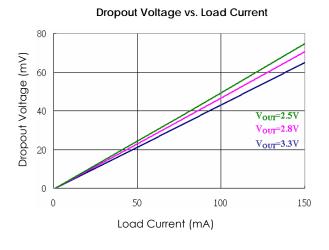


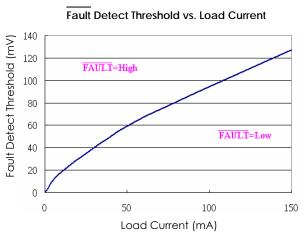
Typical Performance Characteristics Unless otherwise specified, VIN = Vout (NOM) + 0.2V, CIN = COUT =

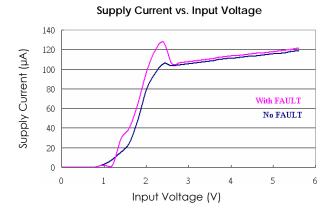


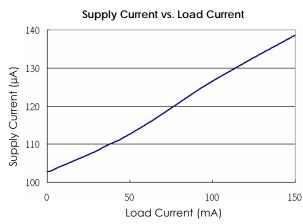


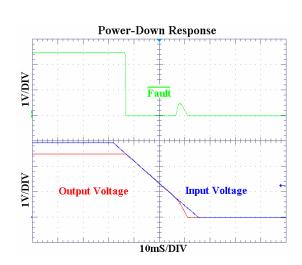
**Typical Performance Characteristics** Unless otherwise specified, VIN =  $V_{OUT\ (NOM)}$  + 0.2V,  $C_{IN}$  =  $C_{OUT}$  = 2.2 $\mu$ F,  $C_{CC}$  = 33nF,  $T_A$  = 25°C,  $V_{SHDN}$  = VIN. (Continued)

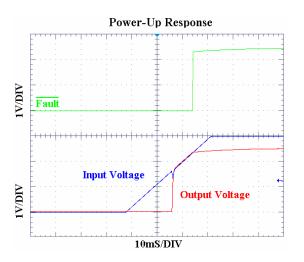






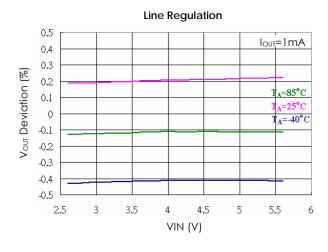


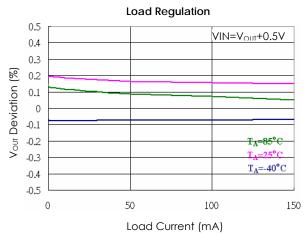






**Typical Performance Characteristics** Unless otherwise specified, VIN =  $V_{OUT (NOM)} + 0.2V$ ,  $C_{IN} = C_{OUT} = 2.2\mu F$ ,  $C_{CC} = 33nF$ ,  $T_A = 25^{\circ}C$ ,  $V_{SHDN} = VIN$ . (Continued)





Publication Date: Mar. 2009 Revision: 5.0 13/21



## **Application Information**

#### **General Description**

Referring to Figure 1 of the Functional Block Diagram, the EMP891X is designed in such a way that a negative feedback control is used to perform the desired voltage regulating function. The negative feedback is formed by using feedback resistors (R1, R2) to sample the output voltage for the non-inverting input of the error amplifier, whose inverting input is set to the bandgap reference voltage. Due to its high open-loop gain, the error amplifier operates to ensure that the sampled output feedback voltage at its non-inverting input is virtually equal to the preset bandgap reference voltage. These feedback resistors can be either internal or external to the EMP891X, depending on whether a preset or an adjustable output voltage version is being used.

To control the amount of current reaching the output, the error amplifier compares the voltage difference at its inputs and produces an appropriate driving voltage to the P-channel MOS pass transistor. If there are changes in the output voltage due to load changes, the feedback resistors register such changes to the non-inverting input of the error amplifier. The error amplifier then adjusts its driving voltage to maintain virtual short between its two input nodes under all loading conditions. Hence, the regulation of the output voltage is achieved as a direct result of the error amplifier keeping its input voltages equal. This negative feedback control topology is further augmented by the shutdown, the fault detection, and the temperature and current protection circuitry.

#### **Output Capacitor**

To take advantage of the savings in cost and space as well as the superior filtering of high frequency noise, the EMP891X is specially designed for use with ceramic output capacitors of as low as 2.2µF. Capacitors of higher value or other types may be used, as long as its equivalent series resistance (ESR) is restricted to less than

 $0.5\,\Omega$ . The use of larger capacitors with smaller ESR values is desirable for applications involving large and fast input or output transients, as well as for situations where the application systems are not physically located immediately adjacent to the battery power source. Typical ceramic capacitors suitable for use with the EMP891X are X5R and X7R. The X5R and the X7R capacitors are able to maintain their capacitance values to within  $\pm 20\%$  and  $\pm 10\%$ , respectively, as the temperature increases.

#### **No-Load Stability**

The EMP891X can maintain stable operation during no-load conditions, a required feature for some applications such as CMOS RAM keep-alive operations.

#### **Input Capacitor**

A minimum input capacitance of 1µF is required for EMP891X. The capacitor value may be increased without limit. Caution should be taken as the instability may result from long supply lead inductance coupling to the output through the gate capacitance of the pass transistor. This will establish a pseudo LCR network, and is likely to happen under high current conditions or near dropout. A 10µF tantalum input capacitor will dampen the parasitic LCR action thanks to its high ESR. However, cautions should be exercised to avoid regulator short-circuit damage when tantalum capacitors are used, for they are prone to fail in short-circuit operating conditions.

#### Compensation (Noise Bypass) Capacitor

To reduce the output voltage noise of the EMP891X, the bypass capacitor  $C_{\rm CC}$  (33nF optimum) can be connected between pin CC and the ground. Because pin CC connects directly to the high impedance output of the bandgap reference circuit, the level of the DC leakage currents in the  $C_{\rm CC}$  capacitors used will adversely reduce the regulator output voltage. This sets the DC leakage level as the key selection criterion of

Publication Date: Mar. 2009 Revision: 5.0 14/21

## Application Information (Continued)

the  $C_{\rm CC}$  capacitor types for use with the EMP891X. NPO and COG ceramic capacitors typically offer very low leakage. Although the use of the  $C_{\rm CC}$  capacitors does not affect the transient response, it does affect the turn-on time of the regulator. Tradeoff exists between output noise level and turn-on time when selecting the  $C_{\rm CC}$  capacitor value.

#### **Power Dissipation and Thermal Shutdown**

Excessive power dissipation may cause thermal overload, and hence the increase of the IC junction temperature beyond a safe operating level. The EMP891X relies on dedicated thermal shutdown circuitry to limit its total power dissipation. An IC junction temperature T<sub>J</sub> exceeding 165°C will trigger the thermal shutdown logic, turning off the P-channel MOS pass transistor. The pass transistor turns on again after the junction cools off by about 30°C.

When continuous thermal overload conditions persist, this thermal shutdown action then results in a pulsed waveform at the output of the regulator. The concept of thermal resistance  $\theta$   $_{JA}$  (°C/W) is often used to describe an IC junction's relative readiness in allowing its thermal energy to dissipate to its ambient air. An IC junction with a low thermal resistance is preferred because it is relatively effective in dissipating its thermal energy to its ambient, thus resulting in a relatively low and desirable junction temperature. The relationship between  $\theta$   $_{JA}$  and  $T_J$  is as follows:

$$T_J = \theta_{JA} (PD) + T_A$$

 $T_A$  is the ambient temperature, and  $P_D$  is the power generated by the IC and can be written as:

$$P_D = I_{OUT} (V_{IN} - V_{OUT})$$

As the above equations indicate, it is desirable to work

with ICs whose  $\theta_{JA}$  values are small such that  $T_J$  does not increase strongly with  $P_D$ . To avoid thermally overloading the EMP891X, refrain from exceeding the absolute maximum junction temperature rating of 150°C under continuous operating conditions. Overstressing the regulator with high loading currents and elevated input-to-output differential voltages can increase the IC die temperature significantly.

#### **Fault Detection**

In the event of the occurrence of various fault conditions that cause failure in the output voltage regulation, such as during thermal overload or current limit, the FAULT pin of the EMP891X becomes low. Because the FAULT pin connects to the open-drain output of a N-channel MOS transistor, a large pull-up resistor (100k  $\Omega$  typical) is required to provide the necessary output voltage and vet compromising the overall power consumption performance of the regulator. The FAULT pin also goes low when the input-to-output differential voltage becomes too small to sustain good load and line regulation at the output. This occurs typically during near dropout when the input-to-output differential voltage is less than 95mV for a load current of 150mA. The EMP891X detects near dropout conditions by comparing the differential voltage against a predefined differential threshold that is always slightly above the dropout voltage. This differential threshold is dynamical in the sense that it not only tracks the dropout voltage as the load current varies, but also scale linearly with the load current.

#### Shutdown

When the  $\overline{SHDN}$  pin is low, the EMP891X enters the sleep mode. When this occurs, the pass transistor, the error amplifier, and the biasing circuits, including the bandgap reference, are turned off, thus reducing the

#### Application Information (Continued)

supply current to typically 1nA. Such a low supply



current makes the EMP891X an ideal device for battery-powered applications. The maximum guaranteed voltage at the  $\overline{SHDN}$  pin for the sleep mode to take effect is 0.4V. A minimum guaranteed voltage of 1.2V at the  $\overline{SHDN}$  pin activates the EMP891X. Direct connection of the  $\overline{SHDN}$  pin to the  $V_{IN}$  to keep the regulator on is allowed for the EMP891X. The  $\overline{SHDN}$  pin must not exceed the supply voltage  $V_{IN}$  under all conditions.

#### Fast Start-Up

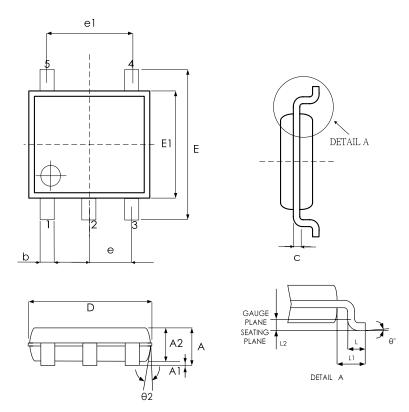
Fast start-up time is one of the important factors for overall system efficiency improvement. The EMP891X has a fast start-up speed when using the optional noise bypass capacitor ( $C_{CC}$ ). To shorten start-up time, the EMP891X internally supplies a 500 $\mu$ A current to charge up the capacitor until it reaches about 95% of its final value.

Publication Date: Mar. 2009 Revision: 5.0 16/21



# **Physical Dimensions**

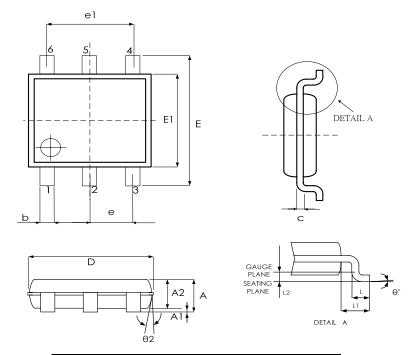
# **SOT-25**



SYMBPLS	MIN.	NOM.	MAX.	
Α	1.05	1.20	1.35	
A1	0.05	0.10	0.15	
A2	1.00	1.10	1.20	
b	0.30		0.50	
С	0.08		0.20	
D	2.80	2.90	3.00	
Е	2.60	2.80	3.00	
El	1.50	1.60	1.70	
е		0.95 BSC		
el		1.90 BSC		
L	0.30	0.45	0.55	
L1	0.60 REF			
θ°	0	5	10	
θ2°	6	8	10	

UNIT: MM

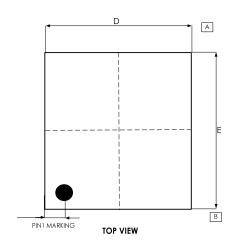
**SOT-26** 

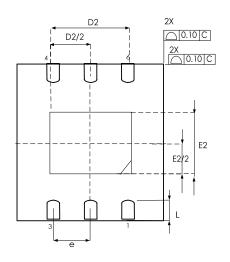


SYMBPLS	MIN.	NOM.	MAX.		
Α	_	_	1.45		
A1			0.15		
A2	0.9	1.15	1.3		
b	0.3		0.5		
С	0.08		0.22		
D	2.90 BSC.				
Е	2.80 BSC.				
E1	1.60 BSC.				
е	0.95 BSC				
e1	1.90 BSC				
L	0.3	0.45	0.6		
L1	0.60 REF				
L2	0.25 REF				
θ°	0	4	8		
Ө2°	5	10	15		

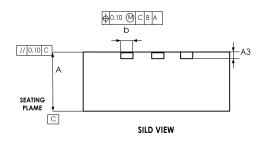
UNIT: MM

TDFN-6





**BOTTOM VIEW** 



	COMMON						
SYMBOL	DIME	nsions mill	IMETER	DIMENSIONS INCH			
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.	
Α	0.70	0.75	0.80	0.027	0.029	0.031	
А3		0.200 REF		0.008 REF			
b	0.25	0.30	0.35	0.010	0.012	0.014	
D		2.00 BSC		0.079 BSC			
D2	1.20	1.30	1.40	0.046	0.050	0.054	
Е		2.00 BSC		0.079 BSC			
E2	0.50	0.60	0.70	0.022	0.024	0.026	
е	0.650 BSC				0.026 BSC		
L	0.25	0.30	0.35	0.009	0.011	0.013	



# **Revision History**

Revision	Date	Description
5.0	2009.03.24	EMP transferred from version 4.1

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Elite Semiconductor Memory Technology Inc.

21/21